

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/082,874	DIEZ ET AL.	
Examiner	Art Unit	
Huyen X. Vo	2626	

	SEARCHED				
Class	Subclass	Date	Examiner		
704	225; 233; 239; 240; 251; 256	2/7/2008	HV ·		
			-		
		_			
		· · <u>- · · ·</u>			

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
-		-		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Update EAST search included	2/8/2008	HV		
<del> </del>				